

**WHAT IS CLAIMED IS:**

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1. (Currently Amended) An integrated circuit device comprising:  
a plurality of internal circuits for generating a plurality of internal signals, the internal signals used for addressing storage locations and for controlling internal operations;  
a selection circuit for controlling transfer paths of the internal signals and data in response to selection signals, the selection signals corresponding to test information signals; and  
a data output buffer for transferring the internal signals external to ~~an outside of~~ the integrated circuit device through data input/output pads.
  
  2. (Currently Amended) An integrated circuit device comprising:  
a plurality of internal circuits for generating a plurality of internal signals, the internal signals used for addressing storage locations and for controlling internal operations;  
a first selection circuit for receiving the internal circuits in response to selection signals corresponding to test information signals;  
a second selection circuit for receiving output signals from the first selection circuit and output signals from a sense amplifier, and for opening an alternative one of transfer paths of the internal signals and the output signals in response to the selection signals; and  
a data output buffer for transferring output signals from the second selection signals external to ~~an outside of~~ the integrated circuit device through data input/output pads.
  
  3. (Currently Amended) A method for monitoring internal signals in an integrated circuit device having input/output pads, the method comprising the steps of:  
detecting a test mode;  
selecting a part of internal signals of the integrated circuit device; and  
transferring the part of the internal signals external to ~~an outside of~~ the integrated circuit device through the input/output pads.

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4. (Currently Amended) A method for monitoring internal signals in an integrated circuit device having sense amplifier, a data output buffer, and input/output pads, the method comprising the steps of:

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detecting a test mode in response to a logical states with external control signals of the integrated circuit device;

selecting a part of internal signals of the integrated circuit device in response to selection signals corresponding to test information signals;

selecting an alternative one of transfer paths of the part of the internal signals and output signals from the sense amplifier in response to the selection signals; and

transferring the part of the internal signals external to ~~an outside~~ of the integrated circuit device through the data output buffer and the input/output pads.

5. (New) The device of claim 1 wherein the internal signals include row information, column information, and control information.

6. (New) The device of claim 1 further comprising:  
a test information input circuit configured to send the selection signals to the selection circuit.

7. (New) The device of claim 6 wherein the test information input circuit is configured to generate the selection signals in correspondence to the test information signals and a test mode signal.

8. (New) The device of claim 7 wherein the test mode signal is in response to dynamic random access memory control information.

9. (New) The device of claim 2 wherein the internal signals include row information, column information, and control information.

10. (New) The device of claim 2 further comprising:

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a test information input circuit configured to send the selection signals to the selection circuit.

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11. (New) The device of claim 10 wherein the test information input circuit is configured to generate the selection signals in correspondence to the test information signals and a test mode signal.

12. (New) The device of claim 10 wherein the test mode signal is in response to dynamic random access memory control information.

13. (New) The method of claim 3 wherein the internal signals are for addressing storage locations and for controlling internal operations.

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14. (New) The method of claim 3 wherein the selecting is based on the detected test mode.

15. (New) The method of claim 3 wherein the detecting is based on dynamic random access memory control information.

16. (New) The device of claim 13 wherein the internal signals include row information, column information, and control information.

17. (New) The system of claim 4 wherein the internal signals are for addressing storage locations and for controlling internal operations.

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18. (New) The method of claim 4 wherein the selection signals also correspond to detected test mode information.

19. (New) The method of claim 4 wherein the logical states are based on dynamic random access memory control information.

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20. (New) The device of claim 17 wherein the internal signals include row information, column information, and control information.